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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

E·XFl

Product Status	Obsolete
Core Processor	C166SV2
Core Size	16-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I ² C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I ² S, POR, PWM, WDT
Number of I/O	75
Program Memory Size	320KB (320K × 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	34K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xe164fn40f80laakxuma1

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



General Device Information

2.1 Pin Configuration and Definition

The pins of the XE164xN are described in detail in **Table 5**, which includes all alternate functions. For further explanations please refer to the footnotes at the end of the table. The following figure summarizes all pins, showing their locations on the four sides of the package.



Figure 3 XE164xN Pin Configuration (top view)



Table	able 5 Pin Definitions and Functions (cont'd)				
Pin	Symbol	Ctrl.	Туре	Function	
6	P7.0	O0 / I	St/B	Bit 0 of Port 7, General Purpose Input/Output	
	T3OUT	01	St/B	GPT12E Timer T3 Toggle Latch Output	
	T6OUT	O2	St/B	GPT12E Timer T6 Toggle Latch Output	
	TDO_A	OH / IH	St/B	JTAG Test Data Output / DAP1 Input/Output If DAP pos. 0 or 2 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.	
	ESR2_1	I	St/B	ESR2 Trigger Input 1	
7	P7.3	O0 / I	St/B	Bit 3 of Port 7, General Purpose Input/Output	
	EMUX1	01	St/B	External Analog MUX Control Output 1 (ADC1)	
	U0C1_DOUT	O2	St/B	USIC0 Channel 1 Shift Data Output	
	U0C0_DOUT	O3	St/B	USIC0 Channel 0 Shift Data Output	
	TMS_C	IH	St/B	JTAG Test Mode Selection Input If JTAG pos. C is selected during start-up, an internal pull-up device will hold this pin low when nothing is driving it.	
	U0C1_DX0F	I	St/B	USIC0 Channel 1 Shift Data Input	
8	P7.1	O0 / I	St/B	Bit 1 of Port 7, General Purpose Input/Output	
	EXTCLK	01	St/B	Programmable Clock Signal Output	
	BRKIN_C	I	St/B	OCDS Break Signal Input	
9	P7.4	O0 / I	St/B	Bit 4 of Port 7, General Purpose Input/Output	
	EMUX2	01	St/B	External Analog MUX Control Output 2 (ADC1)	
	U0C1_DOUT	O2	St/B	USIC0 Channel 1 Shift Data Output	
	U0C1_SCLK OUT	O3	St/B	USIC0 Channel 1 Shift Clock Output	
	тск_с	IH	St/B	DAP0/JTAG Clock Input If JTAG pos. C is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it. If DAP pos. 2 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.	
	U0C0_DX0D	I	St/B	USIC0 Channel 0 Shift Data Input	
	U0C1_DX1E	I	St/B	USIC0 Channel 1 Shift Clock Input	



Tabl	Fable 5 Pin Definitions and Functions (cont'd)				
Pin	Symbol	Ctrl.	Туре	Function	
19	P15.6	I	In/A	Bit 6 of Port 15, General Purpose Input	
	ADC1_CH6	I	In/A	Analog Input Channel 6 for ADC1	
20	V _{AREF}	-	PS/A	Reference Voltage for A/D Converters ADC0/1	
21	V _{AGND}	-	PS/A	Reference Ground for A/D Converters ADC0/1	
22	P5.0	I	In/A	Bit 0 of Port 5, General Purpose Input	
	ADC0_CH0	I	In/A	Analog Input Channel 0 for ADC0	
23	P5.2	I	In/A	Bit 2 of Port 5, General Purpose Input	
	ADC0_CH2	I	In/A	Analog Input Channel 2 for ADC0	
	TDI_A	I	In/A	JTAG Test Data Input	
24	P5.3	I	In/A	Bit 3 of Port 5, General Purpose Input	
	ADC0_CH3	I	In/A	Analog Input Channel 3 for ADC0	
	T3INA	I	In/A	GPT12E Timer T3 Count/Gate Input	
28	P5.4	I	In/A	Bit 4 of Port 5, General Purpose Input	
	ADC0_CH4	I	In/A	Analog Input Channel 4 for ADC0	
	T3EUDA	I	In/A	GPT12E Timer T3 External Up/Down Control Input	
	TMS_A	I	In/A	JTAG Test Mode Selection Input	
29	P5.5	I	In/A	Bit 5 of Port 5, General Purpose Input	
	ADC0_CH5	I	In/A	Analog Input Channel 5 for ADC0	
	CCU60_T12 HRB	I	In/A	External Run Control Input for T12 of CCU60	
30	P5.8	I	In/A	Bit 8 of Port 5, General Purpose Input	
	ADC0_CH8	I	In/A	Analog Input Channel 8 for ADC0	
	ADC1_CH8	I	In/A	Analog Input Channel 8 for ADC1	
	CCU6x_T12H RC	I	In/A	External Run Control Input for T12 of CCU60/1	
	CCU6x_T13H RC	I	In/A	External Run Control Input for T13 of CCU60/1	
	U2C0_DX0F	I	In/A	USIC2 Channel 0 Shift Data Input	



Table	Fin Definitions and Functions (cont'd)				
Pin	Symbol	Ctrl.	Туре	Function	
31	P5.9	I	In/A	Bit 9 of Port 5, General Purpose Input	
	ADC0_CH9	I	In/A	Analog Input Channel 9 for ADC0	
	ADC1_CH9	I	In/A	Analog Input Channel 9 for ADC1	
	CC2_T7IN	I	In/A	CAPCOM2 Timer T7 Count Input	
32	P5.10	I	In/A	Bit 10 of Port 5, General Purpose Input	
	ADC0_CH10	I	In/A	Analog Input Channel 10 for ADC0	
	ADC1_CH10	I	In/A	Analog Input Channel 10 for ADC1	
	BRKIN_A	I	In/A	OCDS Break Signal Input	
	U2C1_DX0F	I	In/A	USIC2 Channel 1 Shift Data Input	
	CCU61_T13 HRA	1	In/A	External Run Control Input for T13 of CCU61	
33	P5.11	I	In/A	Bit 11 of Port 5, General Purpose Input	
	ADC0_CH11	I	In/A	Analog Input Channel 11 for ADC0	
	ADC1_CH11	I	In/A	Analog Input Channel 11 for ADC1	
34	P5.13	I	In/A	Bit 13 of Port 5, General Purpose Input	
	ADC0_CH13	I	In/A	Analog Input Channel 13 for ADC0	
35	P5.15	I	In/A	Bit 15 of Port 5, General Purpose Input	
	ADC0_CH15	I	In/A	Analog Input Channel 15 for ADC0	
36	P2.12	O0 / I	St/B	Bit 12 of Port 2, General Purpose Input/Output	
	U0C0_SELO 4	O1	St/B	USIC0 Channel 0 Select/Control 4 Output	
	U0C1_SELO 3	O2	St/B	USIC0 Channel 1 Select/Control 3 Output	
	READY	IH	St/B	External Bus Interface READY Input	
37	P2.11	O0 / I	St/B	Bit 11 of Port 2, General Purpose Input/Output	
	U0C0_SELO 2	O1	St/B	USIC0 Channel 0 Select/Control 2 Output	
	U0C1_SELO 2	02	St/B	USIC0 Channel 1 Select/Control 2 Output	
	BHE/WRH	ОН	St/B	External Bus Interf. High-Byte Control Output Can operate either as Byte High Enable (BHE) or as Write strobe for High Byte (WRH).	



Tabl	'able 5Pin Definitions and Functions (cont'd)				
Pin	Symbol	Ctrl.	Туре	Function	
39	P2.0	O0 / I	St/B	Bit 0 of Port 2, General Purpose Input/Output	
	AD13	OH / IH	St/B	External Bus Interface Address/Data Line 13	
	RxDC0C	I	St/B	CAN Node 0 Receive Data Input	
	T5INB	I	St/B	GPT12E Timer T5 Count/Gate Input	
40	P2.1	O0 / I	St/B	Bit 1 of Port 2, General Purpose Input/Output	
	TxDC0	01	St/B	CAN Node 0 Transmit Data Output	
	AD14	OH / IH	St/B	External Bus Interface Address/Data Line 14	
	T5EUDB	I	St/B	GPT12E Timer T5 External Up/Down Control Input	
	ESR1_5	I	St/B	ESR1 Trigger Input 5	
41	P2.2	O0 / I	St/B	Bit 2 of Port 2, General Purpose Input/Output	
	TxDC1	01	St/B	CAN Node 1 Transmit Data Output	
	AD15	OH / IH	St/B	External Bus Interface Address/Data Line 15	
	ESR2_5	I	St/B	ESR2 Trigger Input 5	
42	P4.0	O0 / I	St/B	Bit 0 of Port 4, General Purpose Input/Output	
	CC2_CC24	O3 / I	St/B	CAPCOM2 CC24IO Capture Inp./ Compare Out.	
	CS0	OH	St/B	External Bus Interface Chip Select 0 Output	
43	P2.3	O0 / I	St/B	Bit 3 of Port 2, General Purpose Input/Output	
	U0C0_DOUT	01	St/B	USIC0 Channel 0 Shift Data Output	
	CC2_CC16	O3 / I	St/B	CAPCOM2 CC16IO Capture Inp./ Compare Out.	
	A16	ОН	St/B	External Bus Interface Address Line 16	
	ESR2_0	I	St/B	ESR2 Trigger Input 0	
	U0C0_DX0E	I	St/B	USIC0 Channel 0 Shift Data Input	
	U0C1_DX0D	I	St/B	USIC0 Channel 1 Shift Data Input	
	RxDC0A	I	St/B	CAN Node 0 Receive Data Input	



XE164FN, XE164GN, XE164HN, XE164KN XE166 Family / Value Line

General Device Information

Tabl	Table 5 Pin Definitions and Functions (cont'd)			
Pin	Symbol	Ctrl.	Туре	Function
73	P10.7	O0 / I	St/B	Bit 7 of Port 10, General Purpose Input/Output
	U0C1_DOUT	01	St/B	USIC0 Channel 1 Shift Data Output
	CCU60_COU T63	O2	St/B	CCU60 Channel 3 Output
	AD7	OH / IH	St/B	External Bus Interface Address/Data Line 7
	U0C1_DX0B	I	St/B	USIC0 Channel 1 Shift Data Input
	CCU60_CCP OS0A	I	St/B	CCU60 Position Input 0
	T4INB	I	St/B	GPT12E Timer T4 Count/Gate Input
74	P0.7	00 / I	St/B	Bit 7 of Port 0, General Purpose Input/Output
	U1C1_DOUT	01	St/B	USIC1 Channel 1 Shift Data Output
	U1C0_SELO 3	O2	St/B	USIC1 Channel 0 Select/Control 3 Output
	A7	OH	St/B	External Bus Interface Address Line 7
	U1C1_DX0B	I	St/B	USIC1 Channel 1 Shift Data Input
	CCU61_CTR APB	I	St/B	CCU61 Emergency Trap Input
78	P1.0	O0 / I	St/B	Bit 0 of Port 1, General Purpose Input/Output
	U1C0_MCLK OUT	01	St/B	USIC1 Channel 0 Master Clock Output
	U1C0_SELO 4	O2	St/B	USIC1 Channel 0 Select/Control 4 Output
	A8	OH	St/B	External Bus Interface Address Line 8
	ESR1_3	I	St/B	ESR1 Trigger Input 3
	T6INB	I	St/B	GPT12E Timer T6 Count/Gate Input



Tabl	able 5 Pin Definitions and Functions (cont'd)				
Pin	Symbol	Ctrl.		Function	
79	P10.8	O0 / I	St/B	Bit 8 of Port 10, General Purpose Input/Output	
	U0C0_MCLK OUT	01	St/B	USIC0 Channel 0 Master Clock Output	
	U0C1_SELO 0	O2	St/B	USIC0 Channel 1 Select/Control 0 Output	
	U2C1_DOUT	O3	St/B	USIC2 Channel 1 Shift Data Output	
	AD8	OH / IH	St/B	External Bus Interface Address/Data Line 8	
	CCU60_CCP OS1A	I	St/B	CCU60 Position Input 1	
	U0C0_DX1C	I	St/B	USIC0 Channel 0 Shift Clock Input	
	BRKIN_B	I	St/B	OCDS Break Signal Input	
	T3EUDB	I	St/B	GPT12E Timer T3 External Up/Down Control Input	
80	P10.9	O0 / I	St/B	Bit 9 of Port 10, General Purpose Input/Output	
	U0C0_SELO 4	01	St/B	USIC0 Channel 0 Select/Control 4 Output	
	U0C1_MCLK OUT	O2	St/B	USIC0 Channel 1 Master Clock Output	
	AD9	OH / IH	St/B	External Bus Interface Address/Data Line 9	
	CCU60_CCP OS2A	I	St/B	CCU60 Position Input 2	
	TCK_B	IH	St/B	DAP0/JTAG Clock Input If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it. If DAP pos. 1 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.	
	T3INB	1	St/B	GPT12E Timer T3 Count/Gate Input	



Address Area	Start Loc.	End Loc.	Area Size ²⁾	Notes
Reserved for DSRAM	00'8000 _H	00'9FFF _H	8 Kbytes	
External memory area	00'0000 _H	00'7FFF _H	32 Kbytes	

Table 7 XE164xN Memory Map (cont'd)¹⁾

 Accesses to the shaded areas are reserved. In devices with external bus interface these accesses generate external bus accesses.

- 2) The areas marked with "<" are slightly smaller than indicated, see column "Notes".
- 3) The uppermost 4-Kbyte sector of the first Flash segment is reserved for internal use (C0'F000_H to C0'FFFF_H).
- Several pipeline optimizations are not active within the external IO area. This is necessary to control external peripherals properly.

This common memory space consists of 16 Mbytes organized as 256 segments of 64 Kbytes; each segment contains four data pages of 16 Kbytes. The entire memory space can be accessed bytewise or wordwise. Portions of the on-chip DPRAM and the register spaces (ESFR/SFR) additionally are directly bit addressable.

The internal data memory areas and the Special Function Register areas (SFR and ESFR) are mapped into segment 0, the system segment.

The Program Management Unit (PMU) handles all code fetches and, therefore, controls access to the program memories such as Flash memory and PSRAM.

The Data Management Unit (DMU) handles all data transfers and, therefore, controls access to the DSRAM and the on-chip peripherals.

Both units (PMU and DMU) are connected to the high-speed system bus so that they can exchange data. This is required if operands are read from program memory, code or data is written to the PSRAM, code is fetched from external memory, or data is read from or written to external resources. These include peripherals on the LXBus such as USIC or MultiCAN. The system bus allows concurrent two-way communication for maximum transfer performance.

Up to 16 Kbytes of on-chip Program SRAM (PSRAM) are provided to store user code or data. The PSRAM is accessed via the PMU and is optimized for code fetches. A section of the PSRAM with programmable size can be write-protected.

Note: The actual size of the PSRAM depends on the quoted device type.



3.3 Central Processing Unit (CPU)

The core of the CPU consists of a 5-stage execution pipeline with a 2-stage instructionfetch pipeline, a 16-bit arithmetic and logic unit (ALU), a 32-bit/40-bit multiply and accumulate unit (MAC), a register-file providing three register banks, and dedicated SFRs. The ALU features a multiply-and-divide unit, a bit-mask generator, and a barrel shifter.



Figure 5 CPU Block Diagram



3.4 Memory Protection Unit (MPU)

The XE164xN's Memory Protection Unit (MPU) protects user-specified memory areas from unauthorized read, write, or instruction fetch accesses. The MPU can protect the whole address space including the peripheral area. This completes established mechanisms such as the register security mechanism or stack overrun/underrun detection.

Four Protection Levels support flexible system programming where operating system, low level drivers, and applications run on separate levels. Each protection level permits different access restrictions for instructions and/or data.

Every access is checked (if the MPU is enabled) and an access violating the permission rules will be marked as invalid and leads to a protection trap.

A set of protection registers for each protection level specifies the address ranges and the access permissions. Applications requiring more than 4 protection levels can dynamically re-program the protection registers.

3.5 Memory Checker Module (MCHK)

The XE164xN's Memory Checker Module calculates a checksum (fractional polynomial division) on a block of data, often called Cyclic Redundancy Code (CRC). It is based on a 32-bit linear feedback shift register and may, therefore, also be used to generate pseudo-random numbers.

The Memory Checker Module is a 16-bit parallel input signature compression circuitry which enables error detection within a block of data stored in memory, registers, or communicated e.g. via serial communication lines. It reduces the probability of error masking due to repeated error patterns by calculating the signature of blocks of data.

The polynomial used for operation is configurable, so most of the commonly used polynomials may be used. Also, the block size for generating a CRC result is configurable via a local counter. An interrupt may be generated if testing the current data block reveals an error.

An autonomous CRC compare circuitry is included to enable redundant error detection, e.g. to enable higher safety integrity levels.

The Memory Checker Module provides enhanced fault detection (beyond parity or ECC) for data and instructions in volatile and non volatile memories. This is especially important for the safety and reliability of embedded systems.



Functional Description







3.12 A/D Converters

For analog signal measurement, up to two 10-bit A/D converters (ADC0, ADC1) with 11 + 5 multiplexed input channels and a sample and hold circuit have been integrated on-chip. 4 inputs can be converted by both A/D converters. Conversions use the successive approximation method. The sample time (to charge the capacitors) and the conversion time are programmable so that they can be adjusted to the external circuit. The A/D converters can also operate in 8-bit conversion mode, further reducing the conversion time.

Several independent conversion result registers, selectable interrupt requests, and highly flexible conversion sequences provide a high degree of programmability to meet the application requirements. Both modules can be synchronized to allow parallel sampling of two input channels.

For applications that require more analog input channels, external analog multiplexers can be controlled automatically. For applications that require fewer analog input channels, the remaining channel inputs can be used as digital input port pins.

The A/D converters of the XE164xN support two types of request sources which can be triggered by several internal and external events.

- Parallel requests are activated at the same time and then executed in a predefined sequence.
- Queued requests are executed in a user-defined sequence.

In addition, the conversion of a specific channel can be inserted into a running sequence without disturbing that sequence. All requests are arbitrated according to the priority level assigned to them.

Data reduction features reduce the number of required CPU access operations allowing the precise evaluation of analog inputs (high conversion rate) even at a low CPU speed. Result data can be reduced by limit checking or accumulation of results.

The Peripheral Event Controller (PEC) can be used to control the A/D converters or to automatically store conversion results to a table in memory for later evaluation, without requiring the overhead of entering and exiting interrupt routines for each data transfer. Each A/D converter contains eight result registers which can be concatenated to build a result FIFO. Wait-for-read mode can be enabled for each result register to prevent the loss of conversion data.

In order to decouple analog inputs from digital noise and to avoid input trigger noise, those pins used for analog input can be disconnected from the digital input stages. This can be selected for each pin separately with the Port x Digital Input Disable registers.

The Auto-Power-Down feature of the A/D converters minimizes the power consumption when no conversion is in progress.

Broken wire detection for each channel and a multiplexer test mode provide information to verify the proper operation of the analog signal sources (e.g. a sensor system).



3.17 Clock Generation

The Clock Generation Unit can generate the system clock signal f_{SYS} for the XE164xN from a number of external or internal clock sources:

- · External clock signals with pad voltage or core voltage levels
- · External crystal or resonator using the on-chip oscillator
- · On-chip clock source for operation without crystal/resonator
- Wake-up clock (ultra-low-power) to further reduce power consumption

The programmable on-chip PLL with multiple prescalers generates a clock signal for maximum system performance from standard crystals, a clock input signal, or from the on-chip clock source. See also **Section 4.7.2**.

The Oscillator Watchdog (OWD) generates an interrupt if the crystal oscillator frequency falls below a certain limit or stops completely. In this case, the system can be supplied with an emergency clock to enable operation even after an external clock failure.

All available clock signals can be output on one of two selectable pins.



Functional Description

Table 10 Instr	uction Set Summary (cont'd)		
Mnemonic	Description	Bytes	
ROL/ROR	Rotate left/right direct word GPR	2	
ASHR	Arithmetic (sign bit) shift right direct word GPR		
MOV(B)	Move word (byte) data	2/4	
MOVBS/Z	Move byte operand to word op. with sign/zero extension	2/4	
JMPA/I/R	Jump absolute/indirect/relative if condition is met	4	
JMPS	Jump absolute to a code segment	4	
JB(C)	Jump relative if direct bit is set (and clear bit)	4	
JNB(S)	Jump relative if direct bit is not set (and set bit)	4	
CALLA/I/R	Call absolute/indirect/relative subroutine if condition is met	4	
CALLS	Call absolute subroutine in any code segment	4	
PCALL	Push direct word register onto system stack and call absolute subroutine	4	
TRAP	Call interrupt service routine via immediate trap number	2	
PUSH/POP	Push/pop direct word register onto/from system stack	2	
SCXT	Push direct word register onto system stack and update register with word operand	4	
RET(P)	Return from intra-segment subroutine (and pop direct word register from system stack)	2	
RETS	Return from inter-segment subroutine	2	
RETI	Return from interrupt service subroutine	2	
SBRK	Software Break	2	
SRST	Software Reset	4	
IDLE	Enter Idle Mode	4	
PWRDN	Unused instruction ¹⁾	4	
SRVWDT	Service Watchdog Timer	4	
DISWDT/ENWDT	Disable/Enable Watchdog Timer	4	
EINIT	End-of-Initialization Register Lock	4	
ATOMIC	Begin ATOMIC sequence	2	
EXTR	Begin EXTended Register sequence	2	
EXTP(R)	Begin EXTended Page (and Register) sequence	2/4	
EXTS(R)	Begin EXTended Segment (and Register) sequence	2/4	



Electrical Parameters

Sample time and conversion time of the XE164xN's A/D converters are programmable. The timing above can be calculated using Table 20.

The limit values for f_{ADCI} must not be exceeded when selecting the prescaler value.

GLOBCTR.5-0	A/D Converter	INPCRx.7-0	Sample Time ¹⁾
000000 _B	f _{sys}	00 _H	$t_{ADCI} \times 2$
000001 _B	f _{SYS} / 2	01 _H	$t_{ADCI} \times 3$
000010 _B	<i>f</i> _{SYS} / 3	02 _H	$t_{ADCI} \times 4$
:	$f_{\rm SYS}$ / (DIVA+1)	:	$t_{ADCI} \times (STC+2)$
111110 _B	f _{SYS} / 63	FE _H	$t_{ADCI} imes 256$
111111 _B	f _{SYS} / 64	FF _H	$t_{ADCI} imes 257$

 Table 20
 A/D Converter Computation Table

1) The selected sample time is doubled if broken wire detection is active (due to the presampling phase).

Converter Timing Example A:

Assumptions:	$f_{\rm SYS}$	= 80 MHz (i.e. t_{SYS} = 12.5 ns), DIVA = 03 _H , STC = 00 _H
Analog clock	$f_{\sf ADCI}$	$= f_{SYS} / 4 = 20 \text{ MHz}$, i.e. $t_{ADCI} = 50 \text{ ns}$
Sample time	t _S	$= t_{ADCI} \times 2 = 100 \text{ ns}$
Conversion 10	-bit:	
	<i>t</i> _{C10}	= $13 \times t_{ADCI}$ + $2 \times t_{SYS}$ = 13×50 ns + 2×12.5 ns = 0.675 μ s
Conversion 8-I	oit:	
	t _{C8}	= $11 \times t_{ADCI}$ + 2 × t_{SYS} = 11 × 50 ns + 2 × 12.5 ns = 0.575 µs

Converter Timing Example B:

Assumptions:	$f_{\rm SYS}$	= 40 MHz (i.e. t_{SYS} = 25 ns), DIVA = 02 _H , STC = 03 _H
Analog clock	$f_{\sf ADCI}$	$= f_{SYS} / 3 = 13.3 \text{ MHz}$, i.e. $t_{ADCI} = 75 \text{ ns}$
Sample time	t _S	$= t_{ADCI} \times 5 = 375 \text{ ns}$
Conversion 10-	bit:	
	<i>t</i> _{C10}	= $16 \times t_{ADCI}$ + 2 × t_{SYS} = 16 × 75 ns + 2 × 25 ns = 1.25 µs
Conversion 8-b	oit:	
	t _{C8}	= $14 \times t_{ADCI}$ + $2 \times t_{SYS}$ = 14×75 ns + 2×25 ns = 1.10 μ s



Electrical Parameters

Coding of bit fields LEVxV in SWD Configuration Registers

After power-on the supply watch dog is preconfigured to operate in the lower voltage range.

Code	Voltage Level	Notes ¹⁾
0000 _B	-	out of valid operation range
0001 _B	3.0 V	LEV1V: reset request
0010 _B - 0101 _B	3.1 V- 3.4 V	step width is 0.1 V
0110 _B	3.6 V	
0111 _B	4.0 V	
1000 _B	4.2 V	
1001 _B	4.5 V	LEV2V: no request
1010 _B - 1110 _B	4.6 V - 5.0 V	step width is 0.1 V
1111 _B	5.5 V	

Table 22 Coding of bit fields LEVxV in Register SWDCON0

1) The indicated default levels for LEV1V and LEV2V are selected automatically after a power-on reset.

Coding of bit fields LEVxV in PVC Configuration Registers

The core voltages are controlled internally to the nominal value of 1.5 V; a variation of ± 10 % is allowed. These operation conditions limit the possible PVC monitoring values to the predefined reset values shown in Table 23.

Table 23 Coding of bit fields LEVxV in Registers PVCyCONz

Code	Voltage Level	Notes ¹⁾			
000 _B -011 _B	-	out of valid operation range			
100 _B	1.35 V	LEV1V: reset request			
101 _B	1.45 V	LEV2V: interrupt request ²⁾			
110 _B - 111 _B	-	out of valid operation range			

1) The indicated default levels for LEV1V and LEV2V are selected automatically after a power-on reset.

2) Due to variations of the tolerance of both the Embedded Voltage Regulators (EVR) and the PVC levels, this interrupt can be triggered inadvertently, even though the core voltage is within the normal range. It is, therefore, recommended not to use this warning level.



Electrical Parameters

4.6 Flash Memory Parameters

The XE164xN is delivered with all Flash sectors erased and with no protection installed.

The data retention time of the XE164xN's Flash memory (i.e. the time after which stored data can still be retrieved) depends on the number of times the Flash memory has been erased and programmed.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Parameter	Symbol	Values			Unit	Note /
		Min.	Тур.	Max.		Test Condition
Parallel Flash module	$N_{\rm PP}{\rm SR}$	-	-	2 ¹⁾		$N_{\rm FL_RD} \le 1$
program/erase limit depending on Flash read activity		_	-	1 ²⁾		N _{FL_RD} > 1
Flash erase endurance for security pages	$N_{\rm SEC}{ m SR}$	10	-	-	cycles	$t_{\text{RET}} \ge 20 \text{ years}$
Flash wait states ³⁾	N _{WSFLAS} _H SR	1	-	-		f _{SYS} ≤8 MHz
		2	-	-		$f_{\rm SYS} \le 13 \rm MHz$
		3	-	-		$f_{\rm SYS} \le 17 \ \rm MHz$
		4	-	-		$f_{\rm SYS}$ > 17 MHz
Erase time per sector/page	t _{ER} CC	-	7 ⁴⁾	8.0	ms	
Programming time per page	t _{PR} CC	-	34)	3.5	ms	
Data retention time	t _{RET} CC	20	-	-	years	$N_{\rm ER} \le$ 1,000 cycl es
Drain disturb limit	$N_{\rm DD}{\rm SR}$	32	-	-	cycles	
Number of erase cycles	$N_{\sf ER}{\sf SR}$	_	_	15.000	cycles	$t_{\text{RET}} \ge 5$ years; Valid for Flash module 1 (up to 64 kbytes)
		-	-	1.000	cycles	$t_{\text{RFT}} \ge 20$ years

Table 24 Flash Parameters

The unused Flash module(s) can be erased/programmed while code is executed and/or data is read from only one Flash module or from PSRAM. The Flash module that delivers code/data can, of course, not be erased/programmed.



Electrical Parameters



Figure 26 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration where the slave select signal is low-active and the serial clock signal is not shifted and not inverted.



Package and Reliability

Package Outlines



Figure 32 PG-LQFP-100-8 (Plastic Green Thin Quad Flat Package)

All dimensions in mm.

You can find complete information about Infineon packages, packing and marking in our Infineon Internet Page "Packages": http://www.infineon.com/packages

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